## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | LIU ET AL. | Examiner | Art Unit | Nathan W. Ha | 2814 | Page 1 of 1

## U.S. PATENT DOCUMENTS

$\overline{}$	_ Document Number Date				
*		Country Code-Number-Kind Code	MM-YYYY	Name	Classification
	Α	US-2004/0017002 A1	01-2004	Siegel et al.	257/684
	В	US-2004/0017000 A1	01-2004	Chiu et al.	257/678
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

TORCION FAILNI BOOGNENTO						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P.					
	σ					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	х				

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.